
Testing and Verification – *An Introduction*

Testing and Verification of Circuits (CS60089)

Dept. of CSE, IIT Kharagpur



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Course Details

- ❑ **Class Timings:** (Slot: F4)
 - Wednesday: 10:00 AM – 10:55 AM
 - Thursday: 09:00 AM – 09:55 AM
 - Friday: 11:00 AM – 12:55 AM
- ❑ **Venue:** Room No: CSE-120 (Ground Floor, CSE Building)
- ❑ **Course Credits:** 4 (L-T-P: 3-1-0)
- ❑ **Course Web:**
http://cse.iitkgp.ac.in/~aritrah/course/theory/TVC/Autumn2018/CS60089_TV_C_Autumn2018.html
- ❑ **Examinations:**
 - Tutorials (10 x 10 marks = 100 marks): 10%
 - Term-Projects (20+10+20 = 50 marks): 25%
 - Mid-Semester (50 marks): 25%
 - End-Semester (80 marks): 40%
- ❑ **Attendance:** Mandatory (> 80%)
 - failure lead to de-registration from course

Course Agenda

❑ **Design and Simulation Part**

- Design Verification: Introduction and Overview
- Design Entry: *Verilog Basics*
- Simulators: *Working Principle*

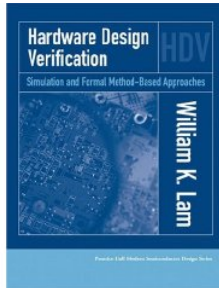
❑ **Design Verification Part**

- Test Scenarios and Coverage: *Test-bench, Simulation Coverage*
- Design Specifications: *LTL, CTL, SVA*
- Symbolic Representation of Logic and State Spaces: *BDDs, SAT*
- Equivalence Checking
- Formal Verification: *Model Checking, Bounded Model Checking*
- Abstraction-Refinement: *CEGAR*
- Formal Verification Coverage

❑ **Circuit Testing Part**

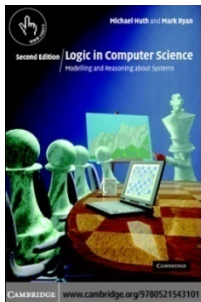
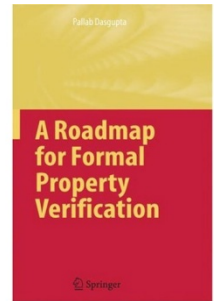
- Test Modeling: Logic and Fault Simulation
- Testability Measures and Analysis
- Test Pattern Generation: **Combinational + Sequential ATPG**
- Design for Testability: **Scan Chain based DFT**
- **Built-in-Self-Test (BIST) and Memory Testing**

Related References (Verification)



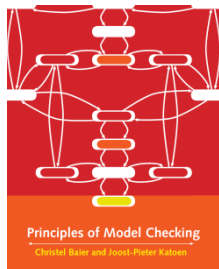
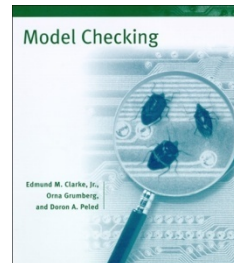
Hardware Design Verification:
Simulation and Formal Method-Based Approaches
William K Lam
Prentice Hall Modern Semiconductor Design Series

A Roadmap for Formal Property Verification
Pallab Dasgupta
Springer



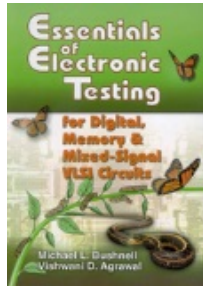
Logic in Computer Science
Michael Huth and Mark Ryan
Cambridge University Press

Model Checking
Edmund M. Clarke, Orna Grumberg
and Doron A. Peled
The MIT Press



Principles of Model Checking
Christel Baier and Joost-Pieter Katoen
The MIT Press

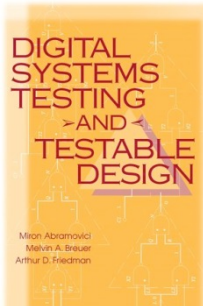
Related References (Testing)



Essentials of Electronic Testing for Digital, Memory and Mixed-Signal VLSI Circuits

Michael L. Bushnell and Vishwani D. Agrawal

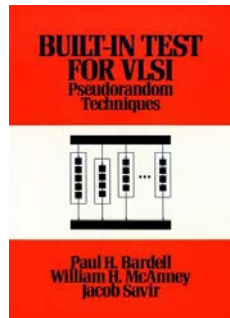
Kluwer Academic Publishers



Digital Systems Testing and Testable Design

Miron Abramovici, Melvin A. Breuer and Arthur D. Friedman

Wiley-IEEE Press



Built-in Test for VLSI: Pseudorandom Techniques

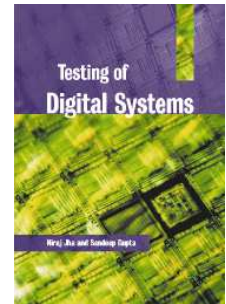
Paul H. Bardell, William H. McAnney and Jacob Savir

Wiley Interscience

Fault Tolerant and Fault Testable Hardware Design

Parag K. Lala

Prentice-Hall International



Testing of Digital Systems

Niraj K. Jha and Sandeep Gupta

Cambridge University Press



VLSI Test Principles and Architectures

Laung-Terng Wang, Cheng-Wen Wu and Xiaoqing Wen

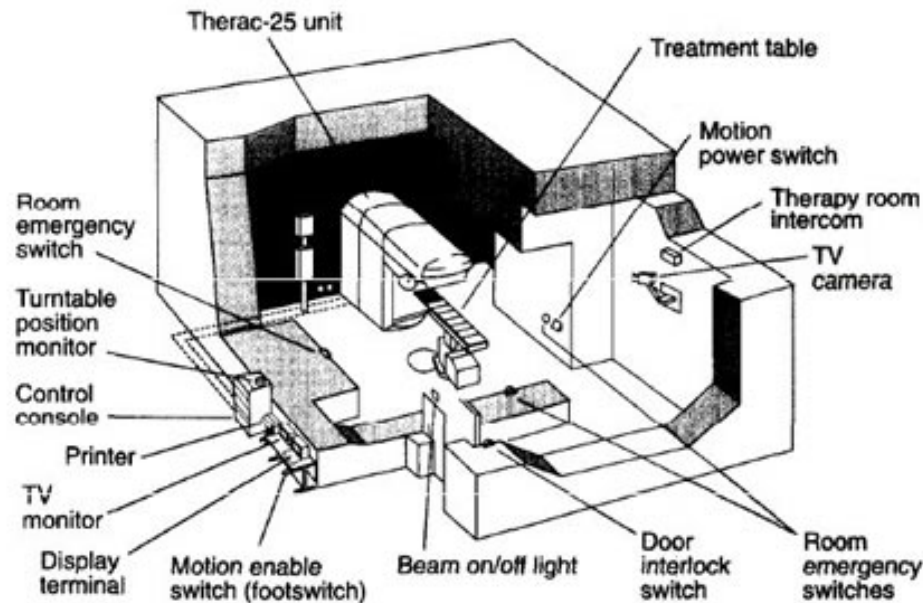
Morgan Kaufman Publishers



Why Testing and Verification?

❑ Therac-25 Radiation Overdosing (1985-1987)

- Radiation machine for treatment of cancer patients
- At least 6 cases of overdoses in 1985-1987 (~100-times doses)
- Three cancer patients died
- Source: **Design error in the control software (race condition)**



Why Testing and Verification?

❑ Shooting Down Airbus 320 (1988)

- US Vincennes shot down Airbus 320
- Mistook Airbus 320 for a F-14
- 290 people died



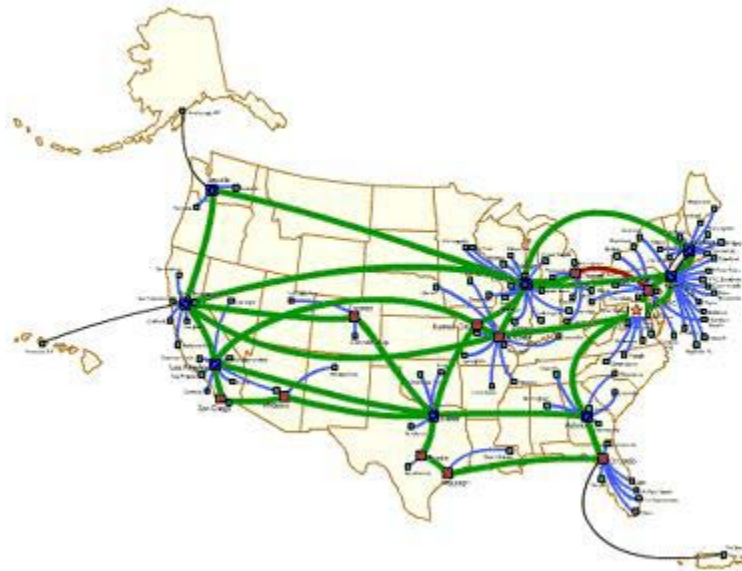
Source:

Software Bug – cryptic and misleading output displayed by the tracking software

Why Testing and Verification?

□ AT&T Telephone Network Outage (1990)

- January 1990: problem in New York City leads to 9-hour outage of large parts of U.S. telephone network
- Costs: several 100 million US\$
- Source: **Software Flaw**
(wrong interpretation of break statement in C)



Why Testing and Verification?

- ❑ **Computer-Aided Ambulance Service in London (1992)**
 - London Ambulance Service computer aided despatch system
 - Area 600sq miles
 - Population 6.8million
 - 5000 patients per day
 - 2000-2500 calls per day
 - 1000-1200 emergency calls
 - Costs: 20-30 people estimated to have died as a result

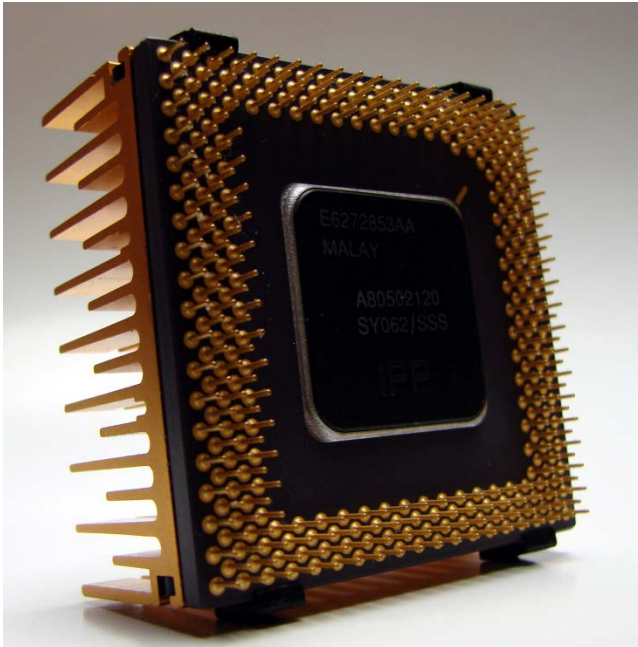
- Source: **position of vehicles incorrectly recorded and multiple vehicles sent to the same location**



Why Testing and Verification?

❑ Pentium FDIV Bug (1994)

- FDIV = Floating-point DIVision unit
- Certain floating-point division operations performed produced incorrect results
- Byte: 1 in 9 billion floating point divides with random parameters would produce inaccurate results
- Loss: 500 million US\$ (all awed processors were replaced) + enormous image loss of Intel Corp.
- Source: **Flawless realization of floating-point division**



Why Testing and Verification?



❑ Ariane 5 Crash (1996)

- Crash of the European Ariane-5 missile in June 1996
- Crashed 40 seconds after Launch
- Costs: more than 500 million US\$

- Source:
 - **Flaw in the control software**
 - **A data conversion from a 64-bit floating-point to 16-bit signed integer**
 - **Efficiency considerations had led to the disabling of the software handler (in Ada)**

Why Testing and Verification?

❑ Anti-lock Braking Problem in Toyota Prius (2010)

- Toyota Prius : first mass-produced hybrid vehicle
- Numerous complaints/accidents
- Source: **Software “glitch” found in anti-lock braking system**
- Costs: Eventually fixed via software update
 - in total 625,000 cars recalled
 - handling of the incident prompted much criticism, bad publicity



We must Test and Verify Automatically!

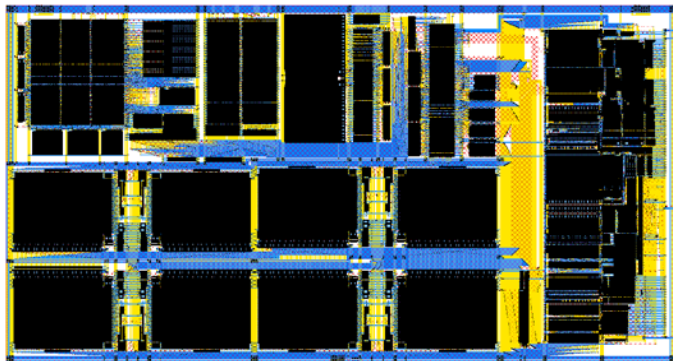
“Testing can only show the presence of errors, not their absence.”

“In their capacity as a tool, computers will be but a ripple on the surface of our Culture. In their capacity as intellectual challenge, computers are without precedent in the cultural history of mankind.”

**To rule out errors must consider all possible executions
– often not feasible mechanically!**



**Edsger Dijkstra
(1930-2002)**

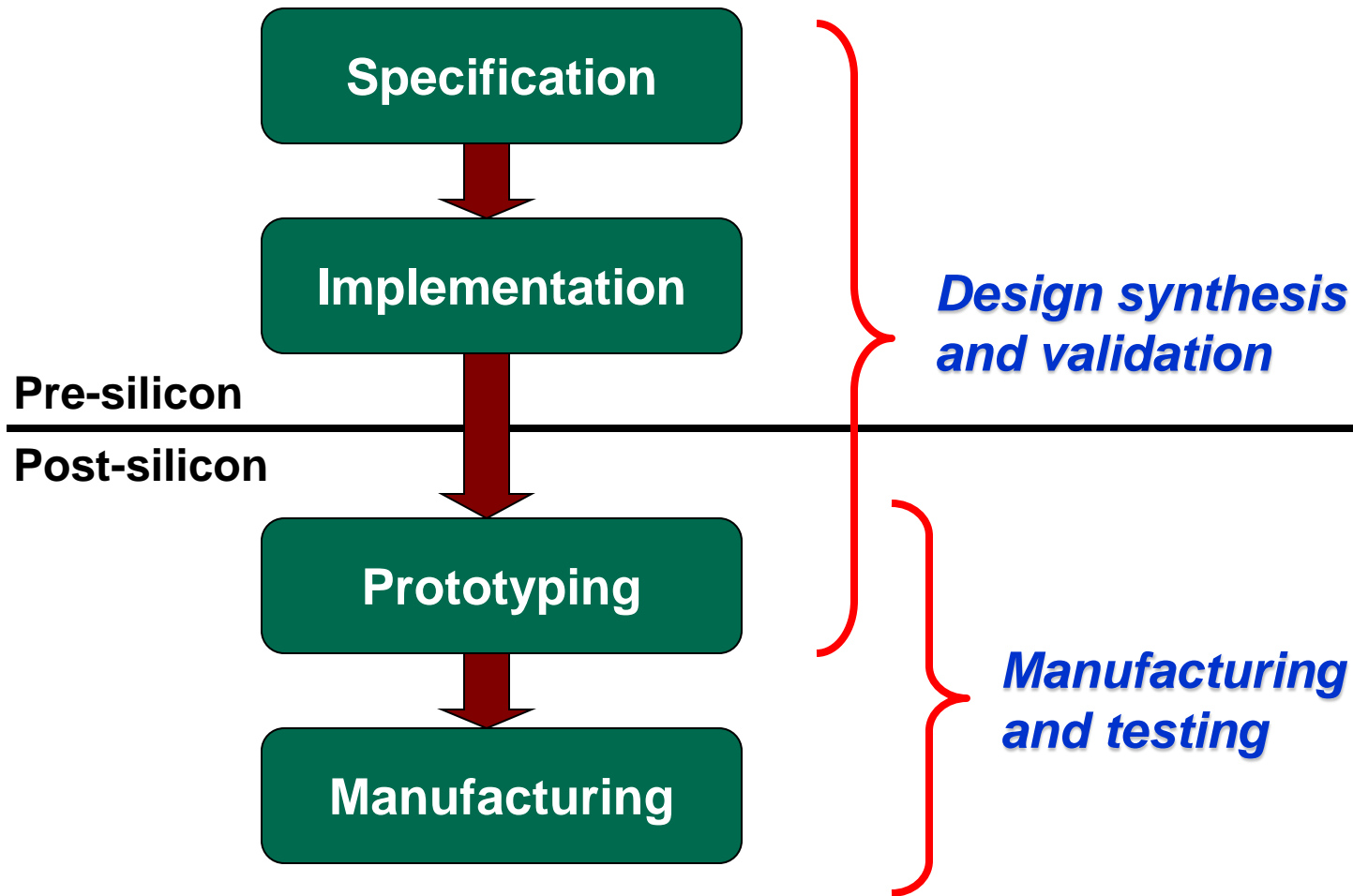


$10^{500,000}$ states

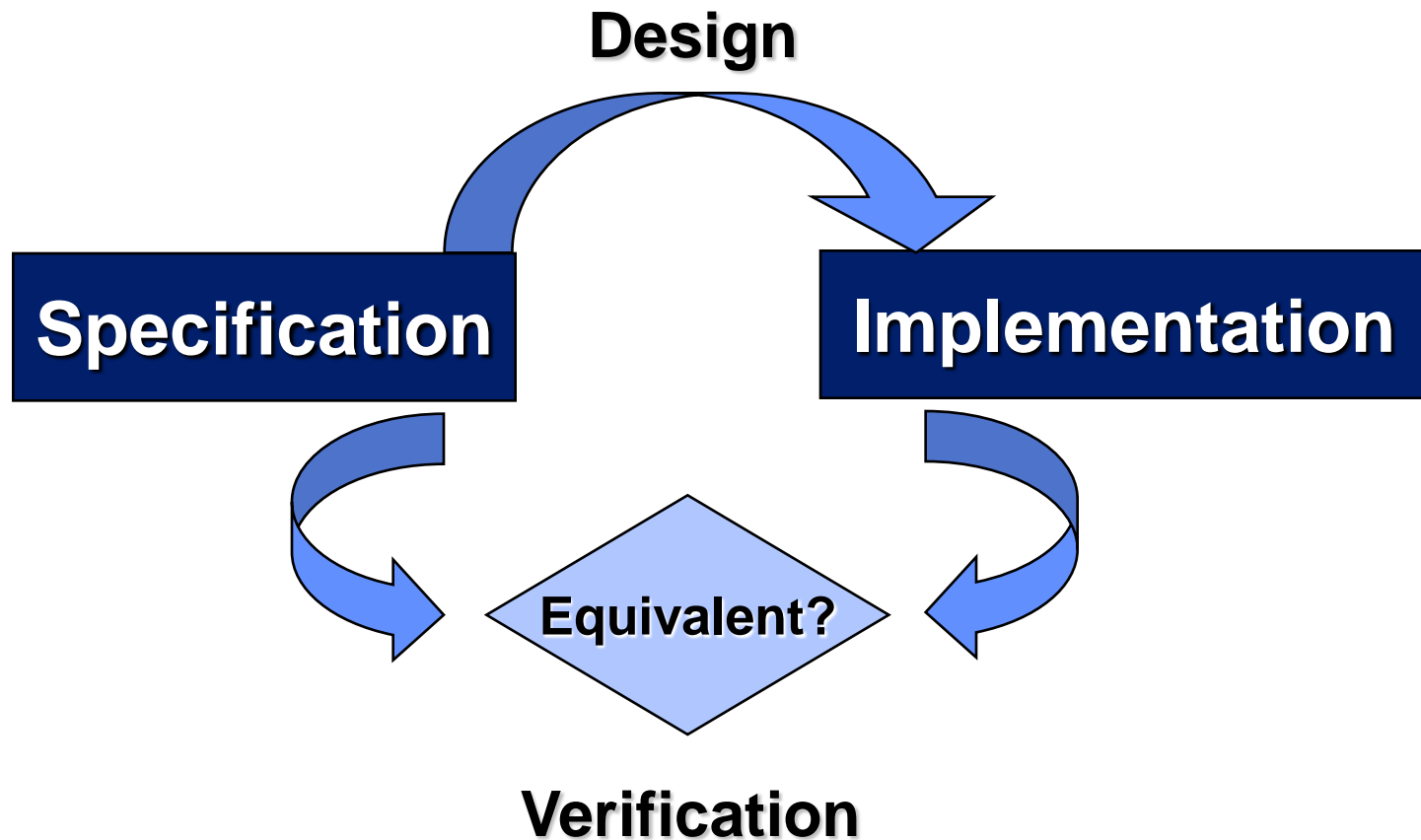


10^{70} atoms

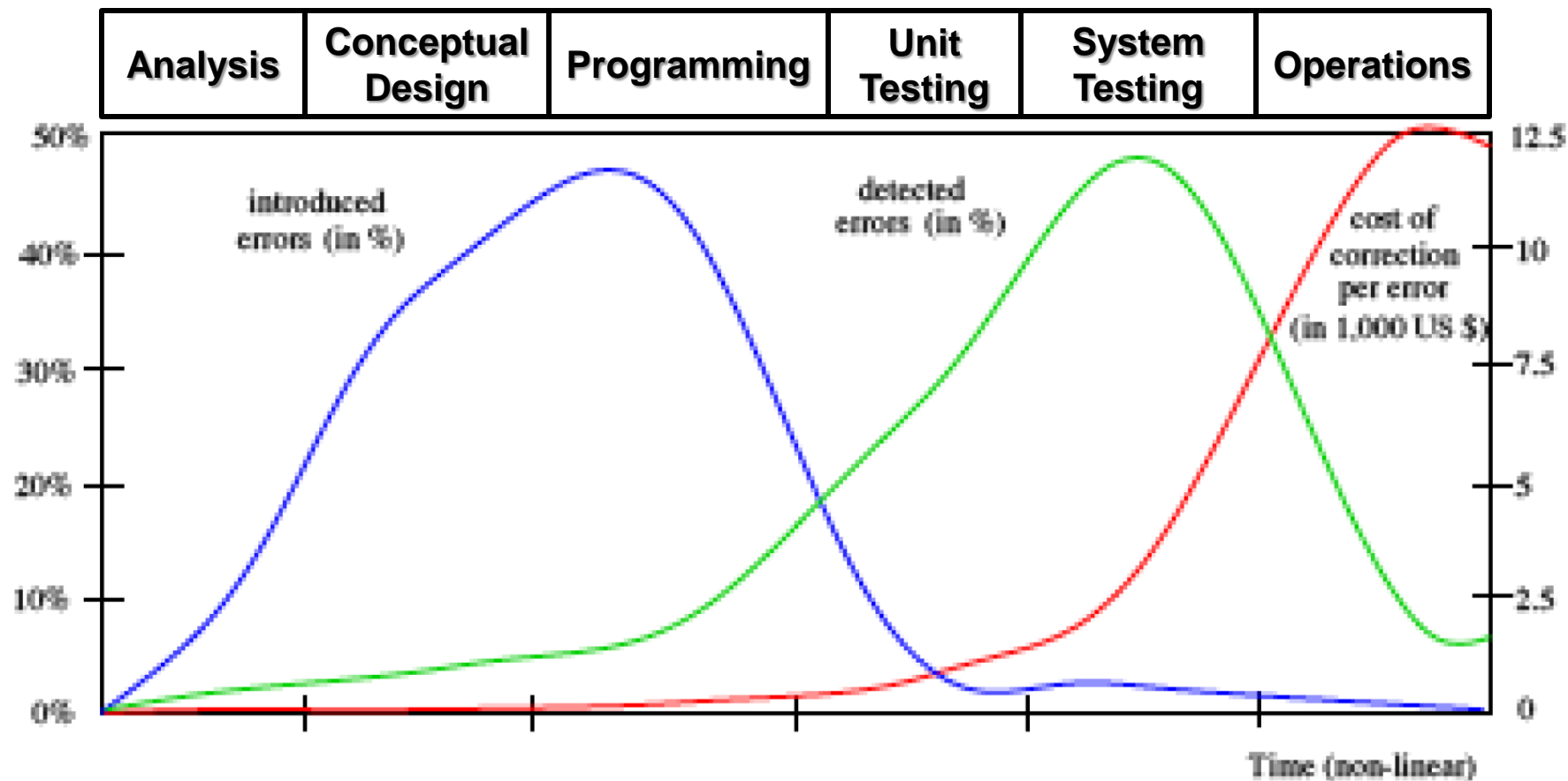
Design, Validation and Testing



Design and Verification



Design Verification: the Sooner, the Better!



Design Challenges

Suppose we have to design
a pacemaker

Resource optimization

Reduce Cost

*Test automation and
Design-for-Test*

Improve Testability

*Algorithms for
better yield*

Improve Reliability

Improve Verifiability

*Verification reliability
and coverage*

Minimize Power

Power optimization during synthesis

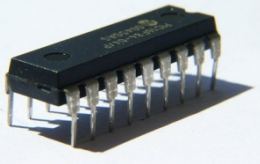
Minimize Area

Area optimization during synthesis

Minimize Delay

Delay optimization during synthesis

Digital Design: Abstraction Levels



Exponential growth
in circuit size
(Moore's Law)

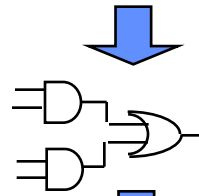
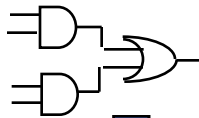
Register Transfer Level

```
always @(posedge clk)
begin
  if (!rst) begin a1 <= a2;
    a2 <= ~a1; end;
end
```

Formalisms introduced at the Entry-Level

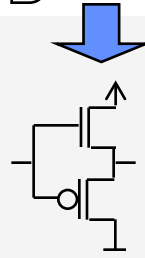
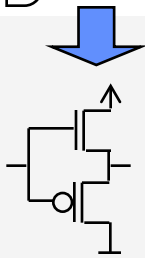
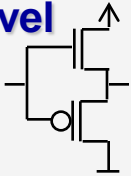
Restricted semantics of
Programming Languages,
Communicating Concurrent
State Machines (CSM)

Gate Level



Boolean Logic
Finite State Machines

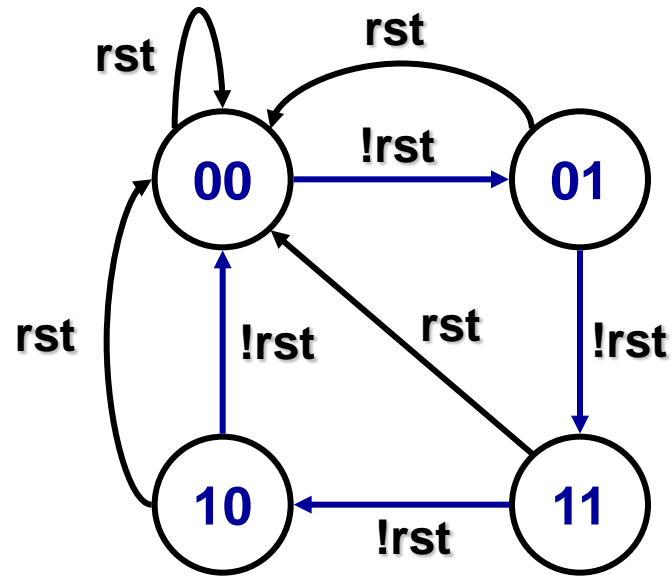
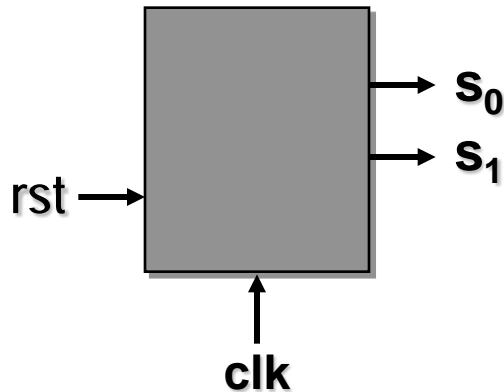
Transistor Level



Schematic

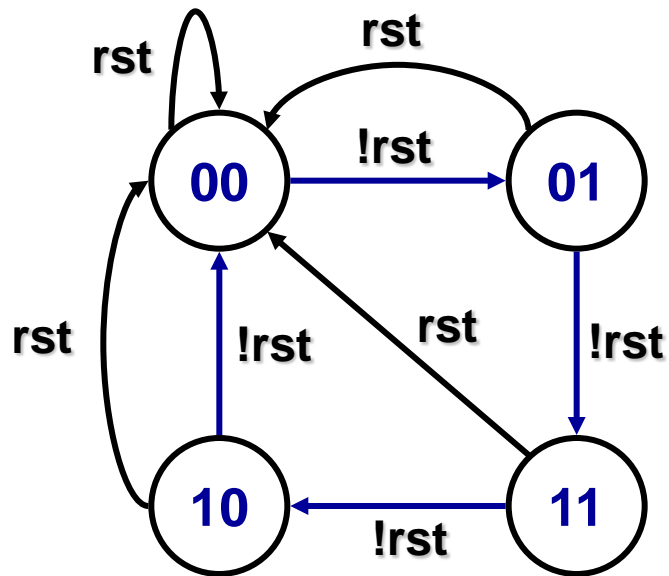
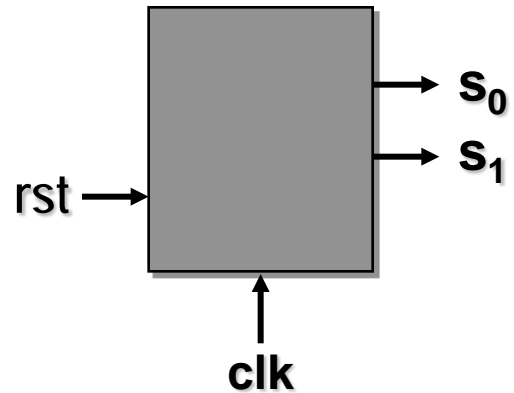
Design Example: 2-bit Gray Counter

Gray Counter: Successive values should differ only in one bit. Reset signal resets the counter to zero.



State m/c Representation

Design Example: 2-bit Gray Counter



State m/c Representation

State Transition Table

(s_0s_1)	rst	(n_0n_1)
00	0	01
00	1	00
01	0	11
01	1	00
10	0	00
10	1	00
11	0	10
11	1	00

Design Example: 2-bit Gray Counter

State Transition Table

(s_0s_1)	rst	(n_0n_1)
00	0	01
00	1	00
01	0	11
01	1	00
10	0	00
10	1	00
11	0	10
11	1	00

State Transition Functions:

$$n_0 = s_0's_1r' + s_0s_1r'$$

$$n_1 = s_0's_1'r' + s_0's_1r'$$

After Logic Minimization:

$$n_0 = s_1r'$$

$$n_1 = s_0'r'$$

Design Example: 2-bit Gray Counter

State Transition Functions:

$$n_0 = s_1 r'$$

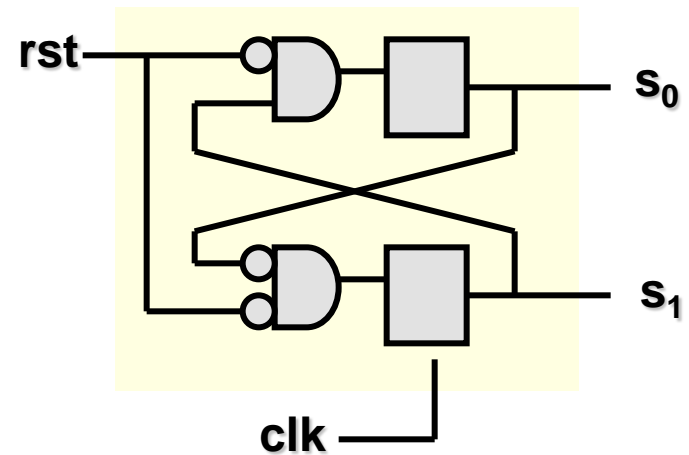
$$n_1 = s_0' r'$$

Verilog Code (RTL):

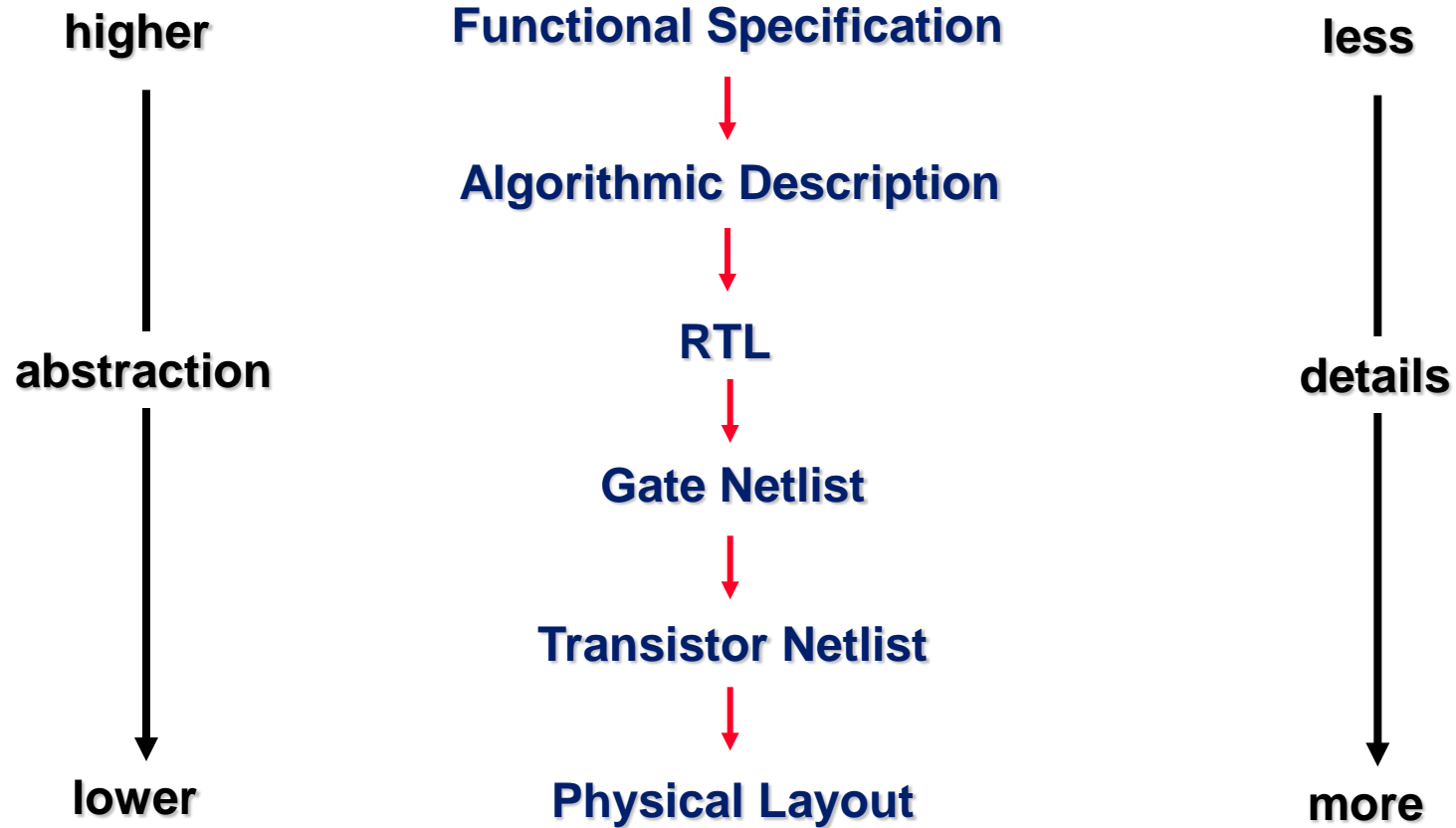
```
module GrayCounter(s0, s1, rst)
input rst;
reg s0, s1;

always @ (posedge clk)
begin
    s0 <= s1 & ~rst;
    s1 <= ~s0 & ~rst;
end
endmodule
```

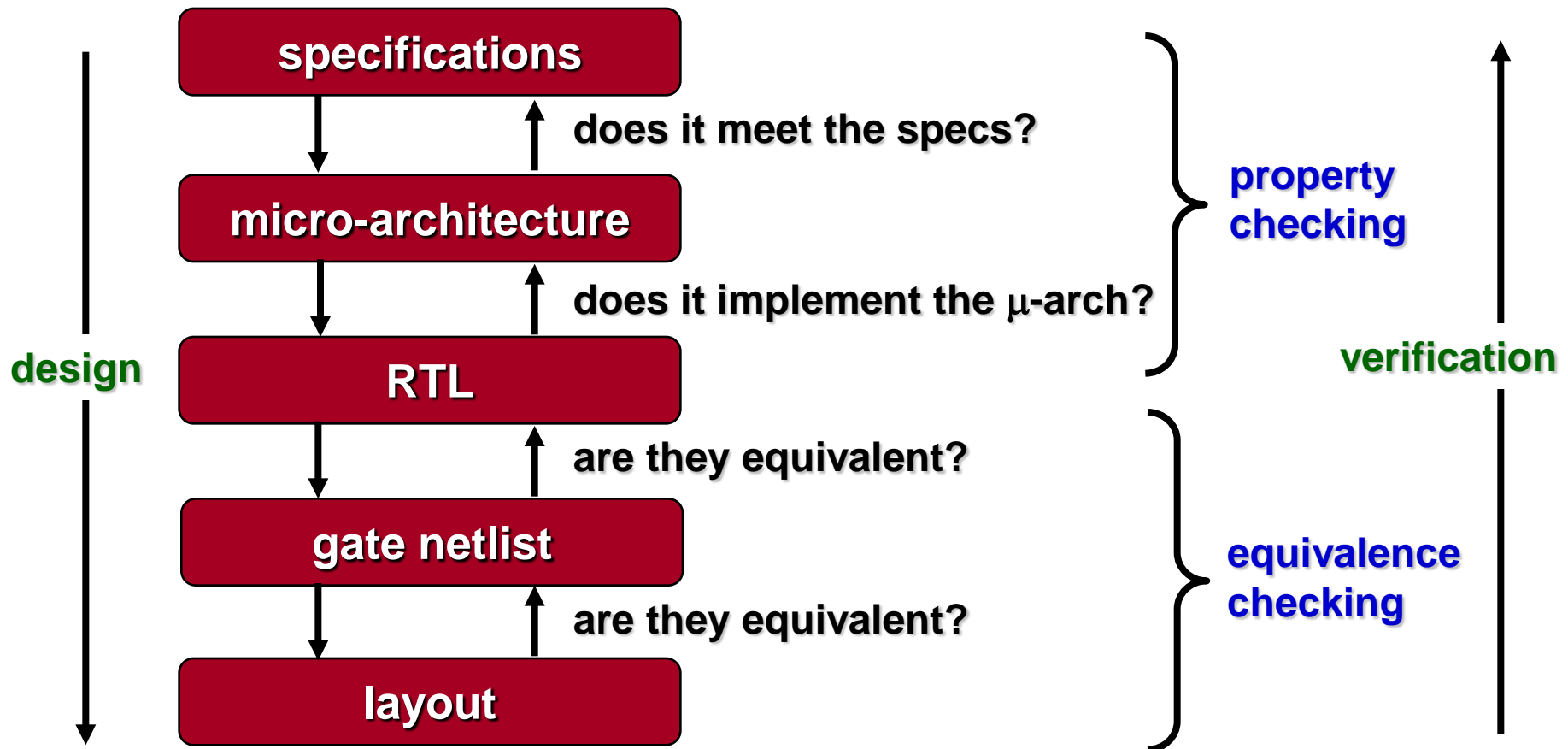
➔
Synthesis



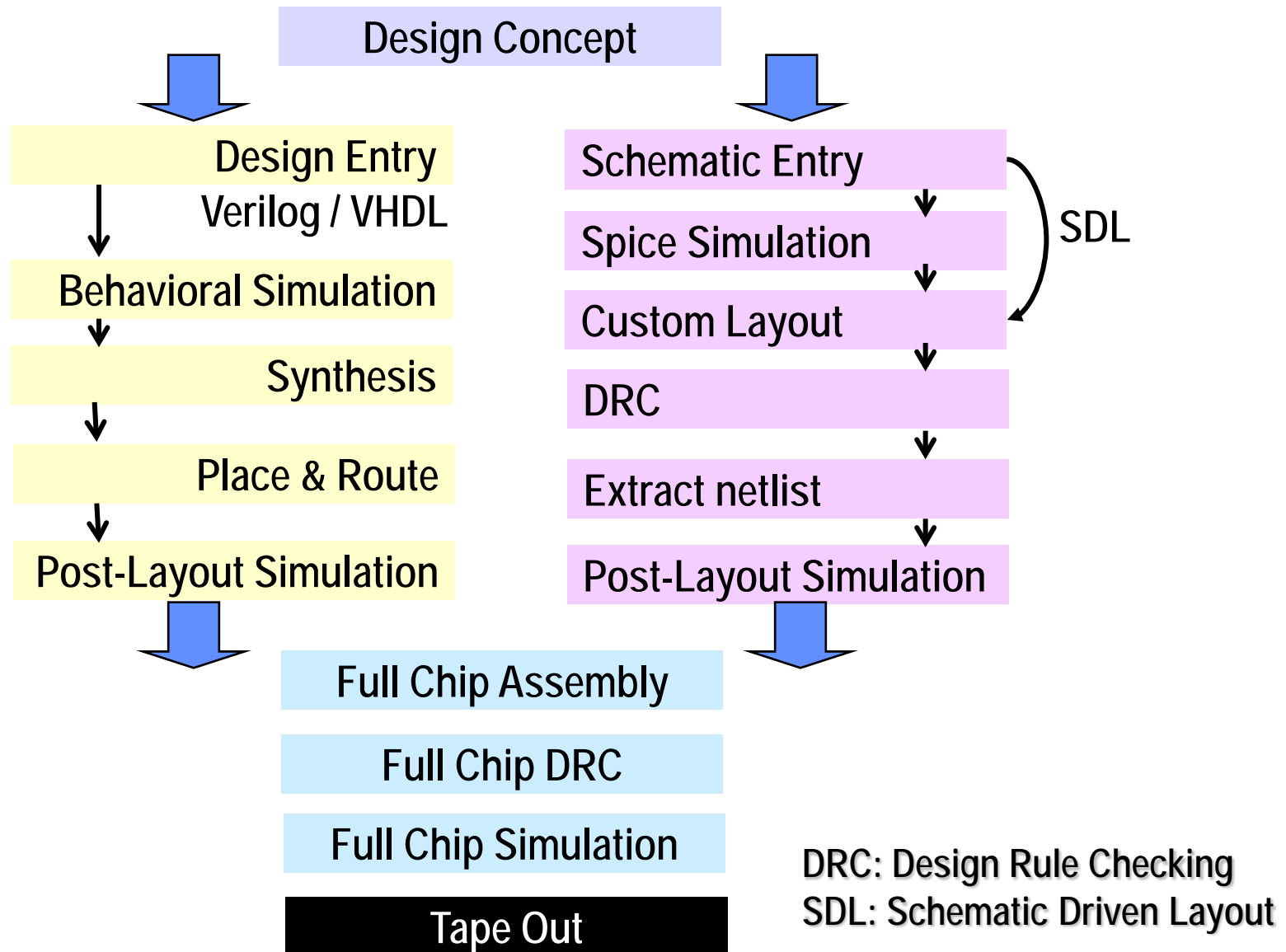
Abstractions in Design Flow



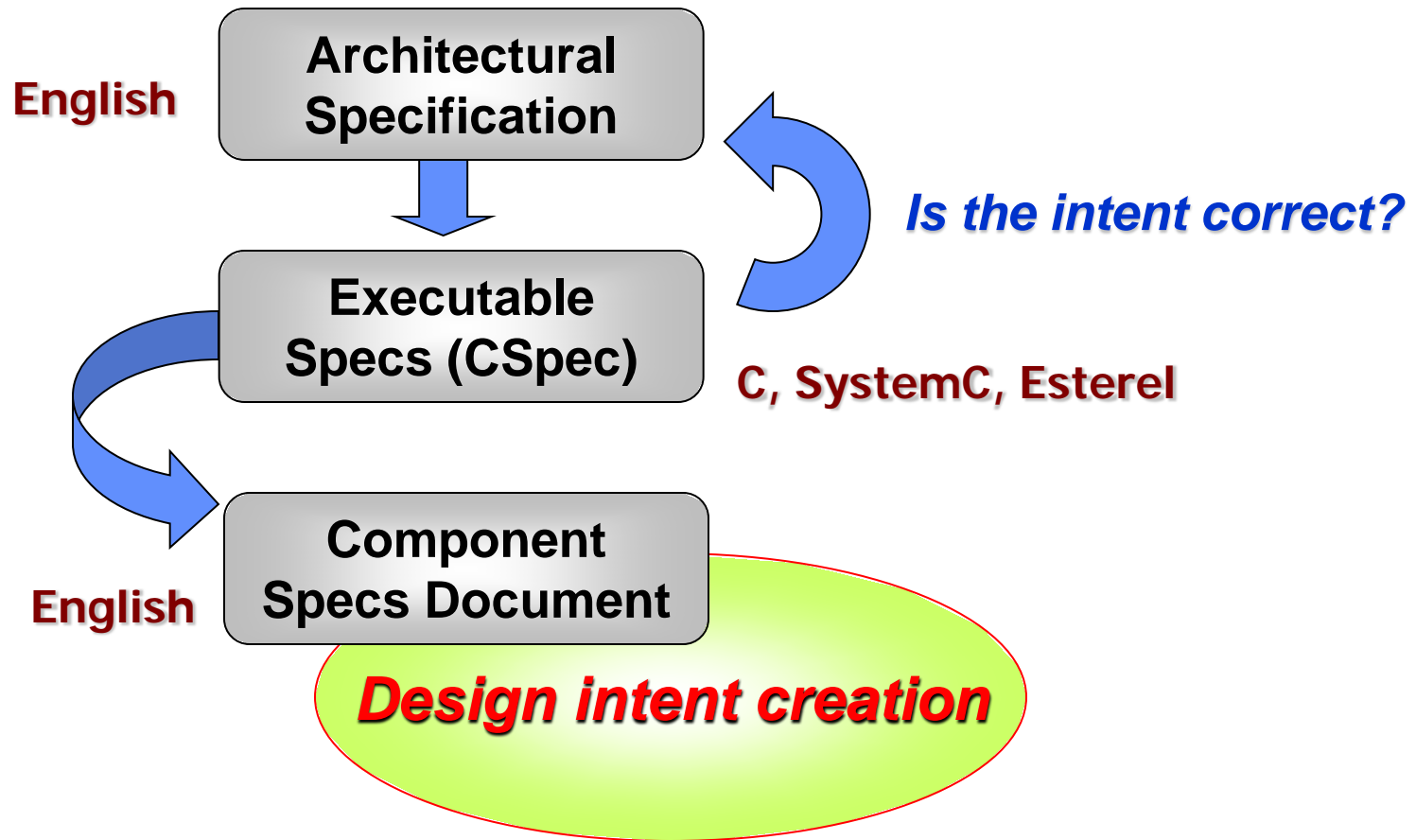
Design and Verification



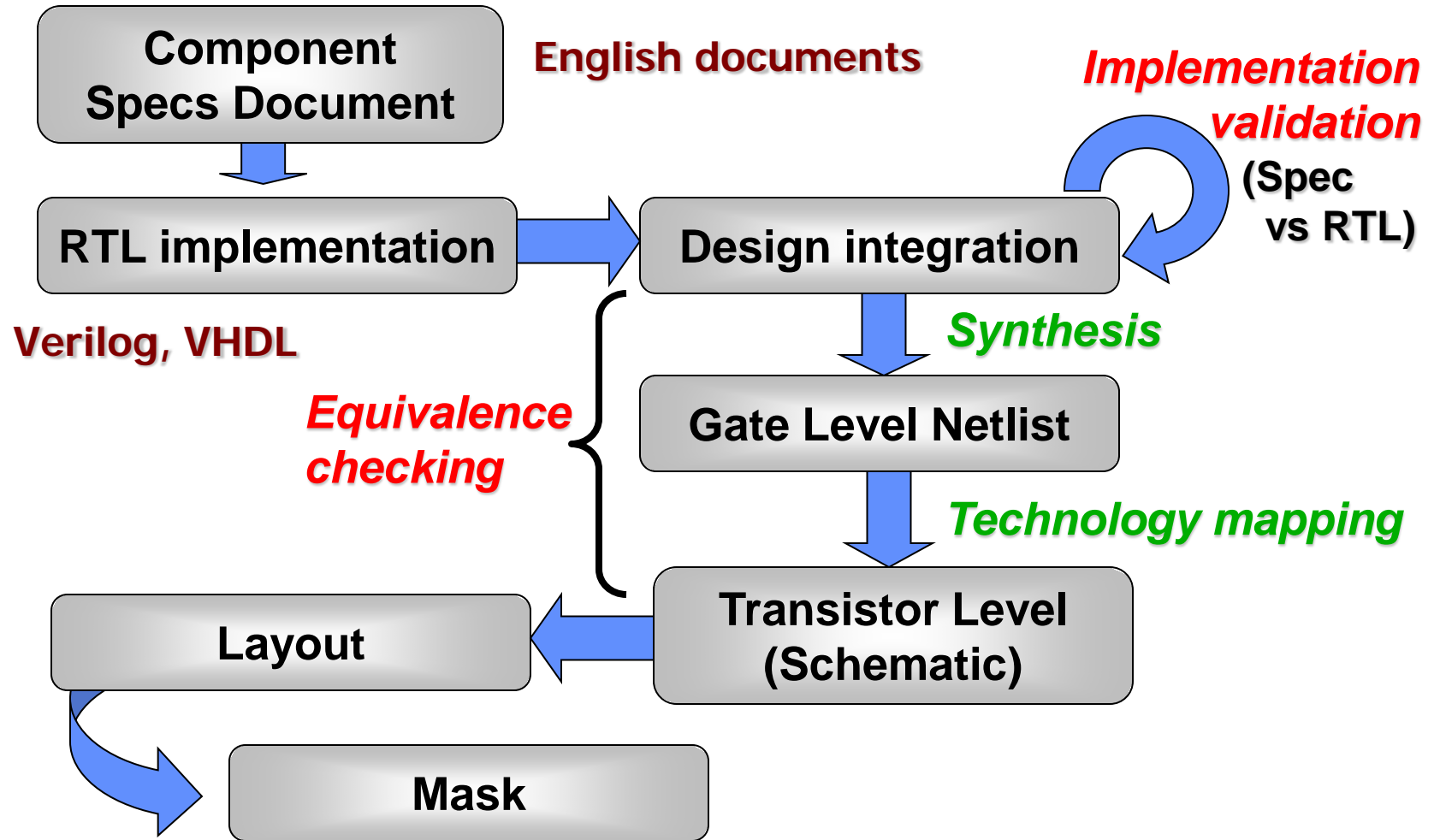
Design Flows: *Digital versus Analog*



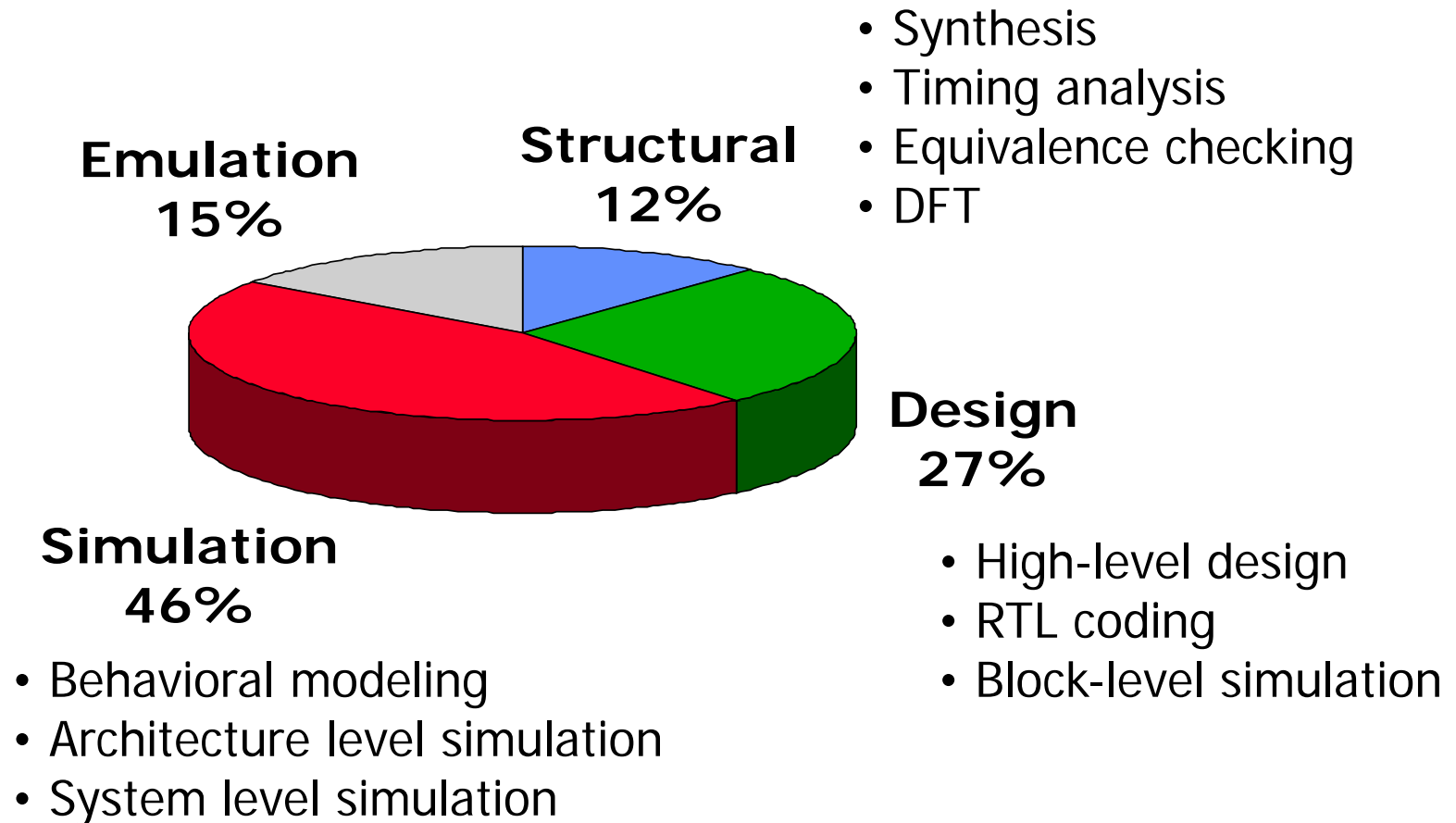
Design Cycle: *Intent Creation*



Design Cycle: *Implementation*

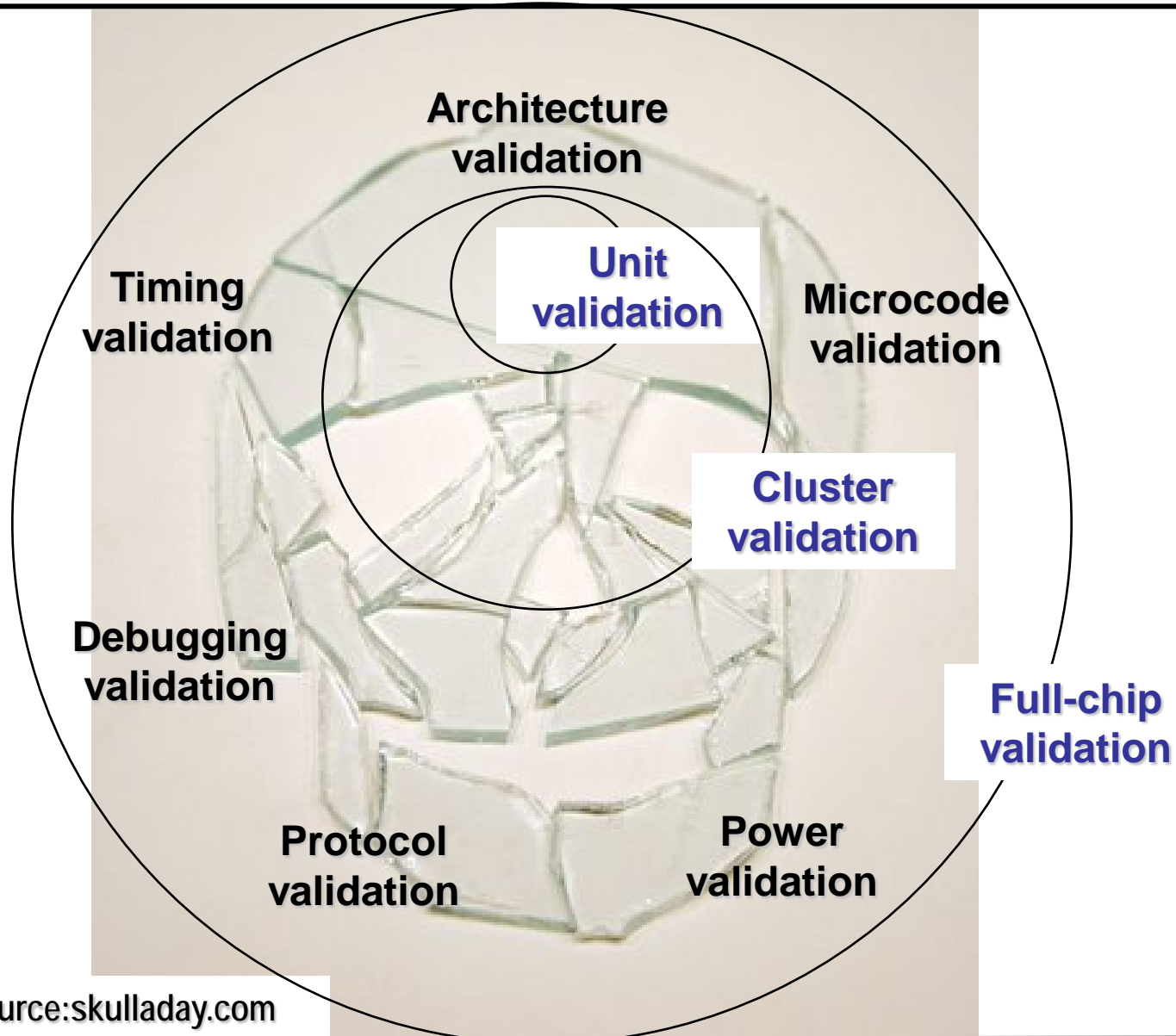


Verification Dominates Design



Source: 0-In Design Automation

Pieces of the verification puzzle



Picture source:skulladay.com